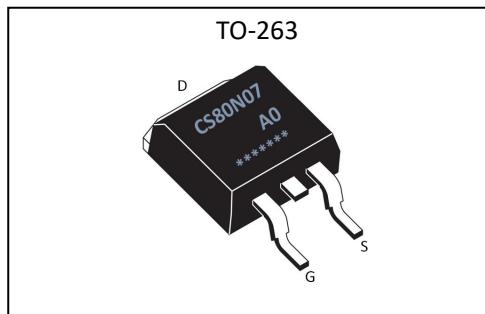


General Description:

The CS80N07A0 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is TO-263, which accords with the RoHS standard.

V_{DSS}	68	V
I_D	80	A
P_D	156	W
$R_{DS(ON)max}$	8.0	$m\Omega$

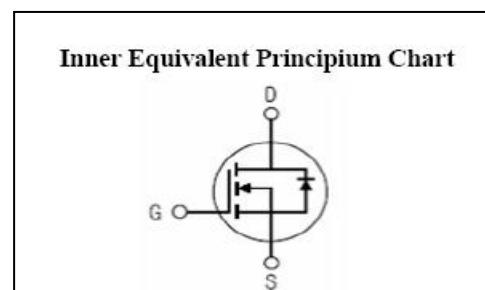


Features:

- Fast Switching
- Low Gate Charge and Rdson
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

Applications:

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Absolute (Tc=25°C unless otherwise specified):

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	70	V
I_D	Continuous Drain Current	80	A
	Continuous Drain Current $T_c=100$ °C	52	A
I_{DM}	Pulsed Drain Current	320	A
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}^{a2}	Single Pulse Avalanche Energy	600	mJ
E_{AR}^{a1}	Avalanche Energy ,Repetitive	50	mJ
I_{AR}^{a1}	Avalanche Current	33	A
dv/dt^{a3}	Peak Diode Recovery dv/dt	5.0	V/ns
P_D	Power Dissipation	156	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	175, -55 to 175	°C
T_L	Maximum Temperature for Soldering	300	°C



CS80N07A0

GL Silicon N-Channel Power MOSFET

Electrical Characteristics ($T_c=25^\circ C$ unless otherwise specified) :

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	68	--	--	V
$\Delta V_{DSS}/\Delta T_j$	Bvdss Temperature Coefficient	$I_D=250\mu A$, Reference $25^\circ C$	--	0.05	--	$V/^\circ C$
I_{DSS}	Drain to Source Leakage Current	$V_{DS}=65V, V_{GS}=0V, T_a=25^\circ C$	--	--	1	μA
		$V_{DS}=56V, V_{GS}=0V, T_a=125^\circ C$	--	--	250	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+20V$	--	--	1	μA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-20V$	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=40A$	--	6.5	8.0	$m\Omega$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	2.9	4.0	V
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Transconductance	$V_{DS}=5V, I_D=40A$	15	--	--	S
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=60V$	--	3396	--	pF
C_{oss}	Output Capacitance	$f=1.0MHz$	--	435	--	
C_{rss}	Reverse Transfer Capacitance		--	151	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time		--	15	--	ns
t_r	Rise Time	$I_D=40A, V_{DD}=35V$	--	44	--	
$t_{d(OFF)}$	Turn-Off Delay Time	$V_{GS}=10V, R_G=3.0\Omega$	--	31	--	
t_f	Fall Time		--	15	--	
Q_g	Total Gate Charge	$I_D=40A, V_{DD}=35V$	--	58	--	nC
Q_{gs}	Gate to Source Charge	$V_{GS}=10V$	--	22	--	
Q_{gd}	Gate to Drain ("Miller")Charge		--	15	--	

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	80	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	320	A
V_{SD}	Diode Forward Voltage	$I_S=80A, V_{GS}=0V$	--	--	1.5	V
t_{rr}	Reverse Recovery Time	$I_S=40A, T_j = 25^\circ C$	--	33	--	ns
Q_{rr}	Reverse Recovery Charge	$dI_F/dt=100A/\mu s, V_{GS}=0V$	--	56	--	nC
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case	0.8	°C/W

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

^{a2}: EAS condition : $T_j=25^\circ C, V_{DD}=30V, V_G=10V, L=0.5mH, R_g=25\Omega$

^{a3}: $I_{SD} = 80A, dI/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}, \text{Start } T_j=25^\circ C$

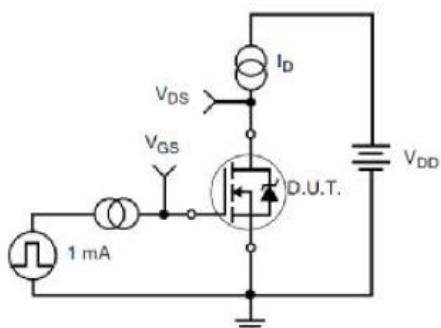
Test Circuit and Waveform


Figure 17. Gate Charge Test Circuit

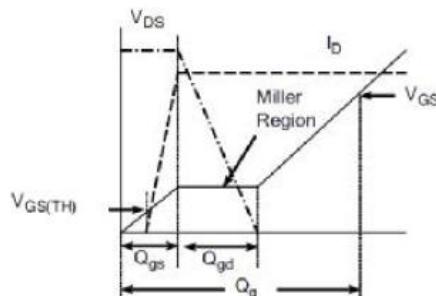


Figure 18. Gate Charge Waveform

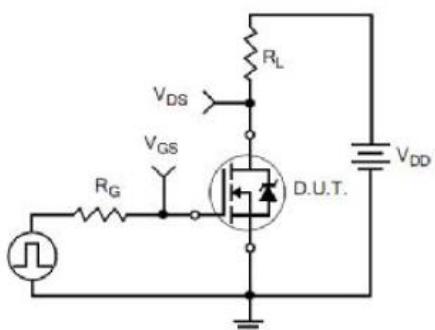


Figure 19. Resistive Switching Test Circuit

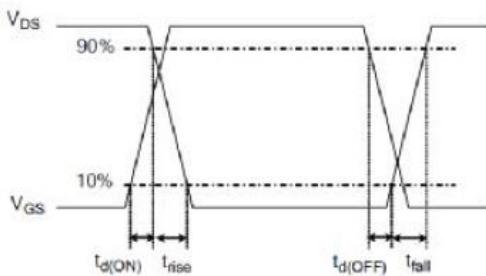


Figure 20. Resistive Switching Waveforms

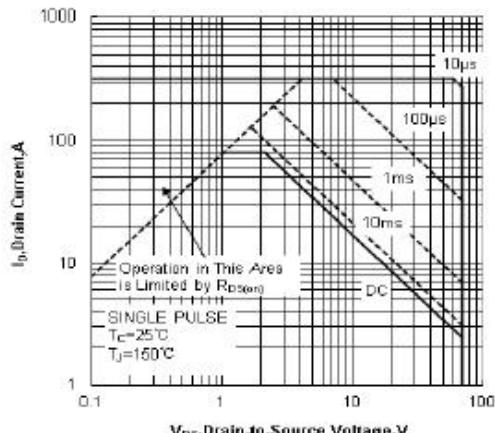
Characteristics Curve:


Figure 1 Maximum Forward Bias Safe Operating Area

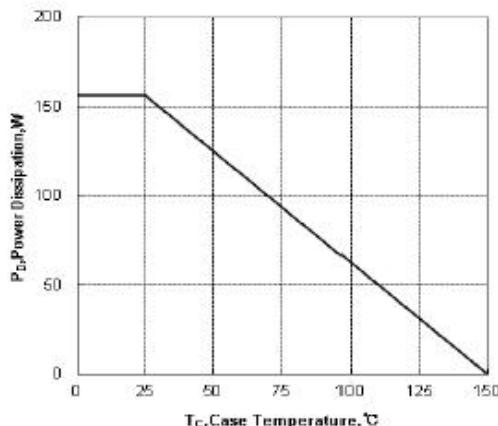


Figure 2 Maximum Power Dissipation vs Case Temperature

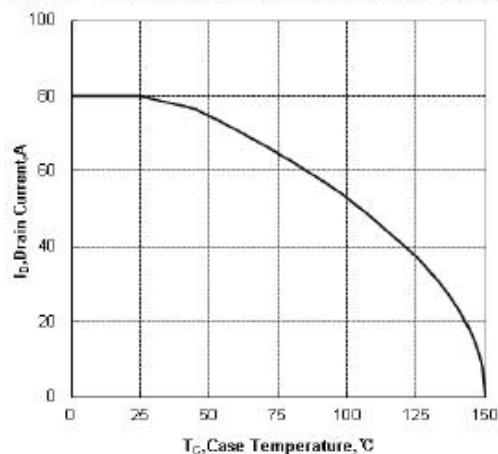


Figure 3 Maximum Continuous Drain Current vs Case Temperature

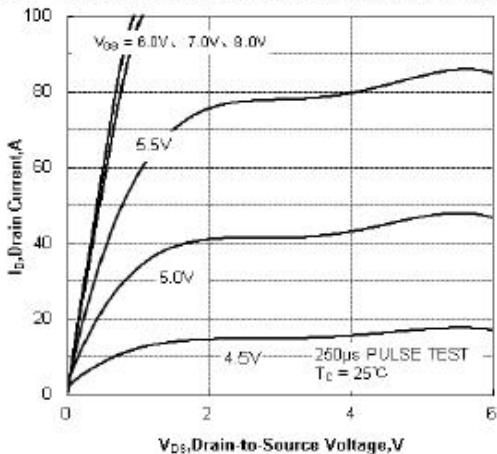


Figure 4 Typical Output Characteristics

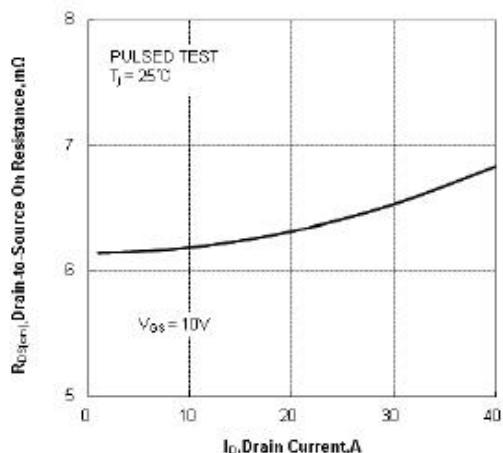


Figure 5 Drain-to-Source On Resistance vs Drain Current

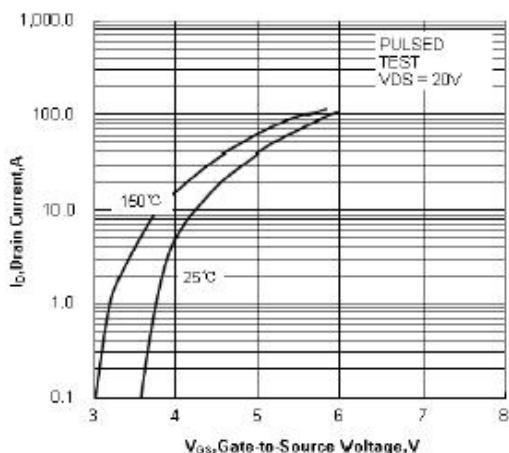


Figure 6 Typical Transfer Characteristics

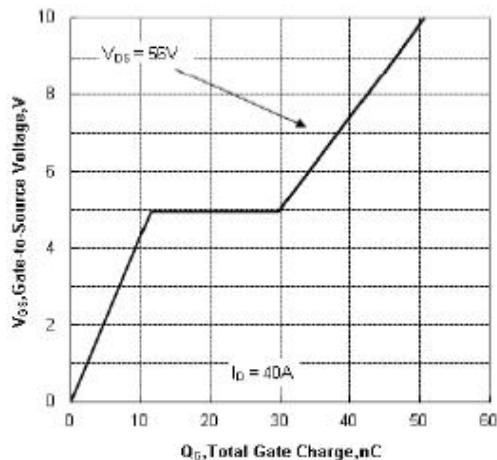


Figure 7 Typical Gate Charge vs Gate to Source Voltage

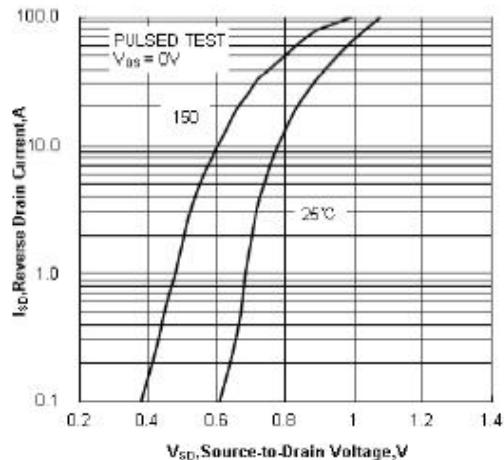


Figure 8 Typical Body Diode Transfer Characteristics

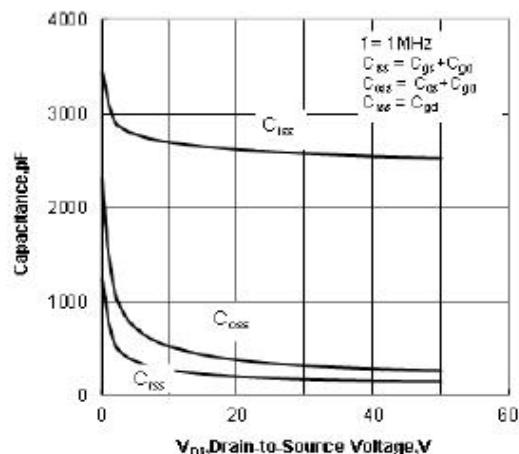


Figure 9 Typical Capacitance vs Drain to Source Voltage

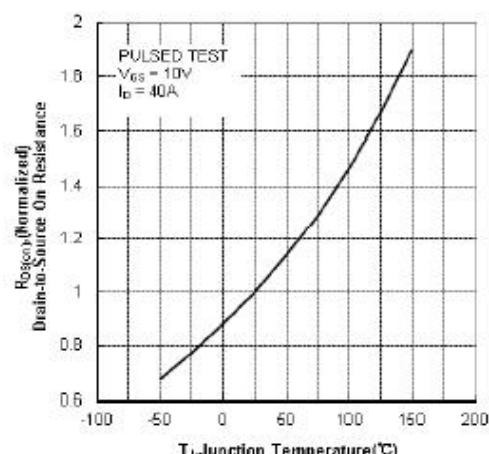


Figure 10 Typical Drian to Source on Resistance vs Junction Temperature

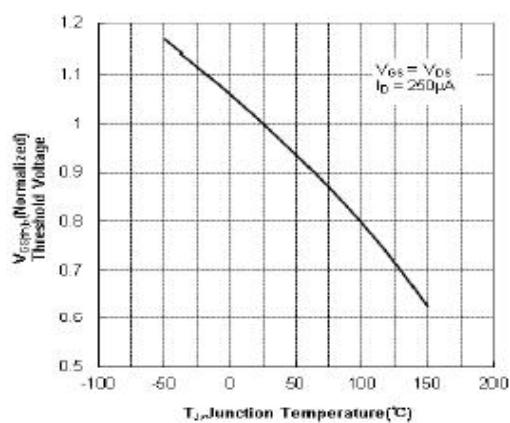


Figure 11 Typical Threshold Voltage vs Junction Temperature

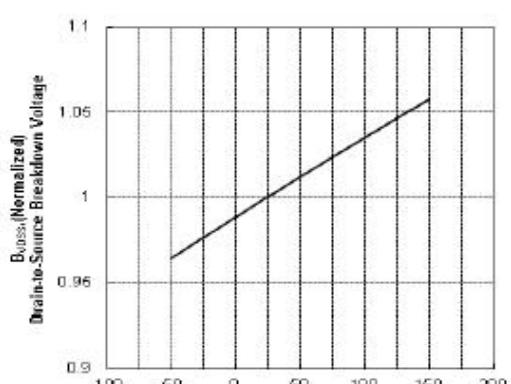


Figure 12 Typical Breakdown Voltage vs Junction Temperature